

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination BAEK ET AL.	
		Examiner Minh-Loan T. Tran	Art Unit 2826	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,074,102	06-2000	Oikawa, Yoichi	385/88
	B	US-6,836,492	12-2004	Ido et al.	372/36
	C	US-2004/0247259	12-2004	Blom, Claes	385/092
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 02/078409	10-2002	WO	Blom et al.	H05K 1/18
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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